**Q.1** 

AFM tips and cantilever assembly are made from which material vi) (a) SiN (b) GaAs (c) InSb (d) Ge vii)  $MgK_{\alpha}$  radiation is used in which technique (a)X-ray diffraction (b) XPS (c) SIMS (d) AES

(c) velocity

(b) wavelength

(a) frequency

Pyrolytic and Photolytic process are related to which method (a)PECVD (b) HTCVD (c) MOCVD (d) LECVD

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(d)deposition rate

(8)

- i) How Auger electron are produced and explain how one can do depth profiling studies with AES?
- ii) In which form sample is required for TEM? State the two different modes of TEM and explain them in short.
- Discuss how MOCVD reaction can be used to deposit semiconductor epitaxial film using chemical equation.
- iv) Differentiate between evaporation and sputtering techniques.
- v) Explain in short how RHEED and LEED differs from each other.
- vi) Derive the expression for critical size nuclei in the case of capillarity model.
- vii) Mention the two conditions required for single electron tunneling?
- viii) What is lithography? Why it has gained popularity since last few decades?
- ix) Explain what is meant by thermal accommodation coefficient.
- Q.3(a) Using schematic diagrams explain the working principle of Atomic force microscope. (6)
- Q.3(b) Describe different techniques by which carbon nanotubes can be (6) synthesized.

## OR

- Q.3(b) By drawing the lay out diagram describe construction and working of (6) Scanning tunneling microscope.
- Q.4(a) State different stages involved in the growth of thin films and explain each of them in detail with suitable diagaram. (6)
- Q.4(b) With the help of the relevant expressions explain atomistic theory in (6) detail.

## OR

Q.4(b) Explain techniques known to you for measurement of thickness of thin (6) films.

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- Q.5(a) Why RF sputtering is suitable for depositing insulating films? Explain this technique in detail.
  Q.5(b) State the advantage of molecular beam epitaxy over liquid phase epitaxy technique. Discuss in detail MBE method for depositing monolayer films.
- Q.5(b) Explain ion plating technique with suitable diagram used for depositing (6) thin films.

OR

- Q.6(a) Describe in detail SEM technique used for studying surface morphology of (6) the sample.
- Q.6(b) How Rutherford back scattering(RBS) is useful in analyzing thin film (6) samples? Explain it in detail.

OR

Q.6(b) Discuss how X-ray photoelectron spectroscopy (XPS) is helpful in (6) elemental idenfication.

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